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Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
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<i>SL</i>	Suk Shin et al.: "Characteristics of Pt/SrTi03/Pb(Zr0.52,Ti0.48)03/SrTi03/Si Ferroelectric Gate Oxide Structure", Preparation and Characterization, Elsevier Sequoia, NL, vol. 354, no. 1-2, October 8, 1999, pgs.251-255, XP004321418 ISSN: 0040-6090, abstract; figure 2; table 1.
<i>SL</i>	Lee Chang et al.: "Single and Multilayer Ferroelectric PbZrxTi1-x03 (PZT) on BaTi03", Thin Solid Films, Elsevier-Sequoia S.A. Lausanne, CH., vol. 303, no. 1-2, July 15, 1997, pgs. 94-100, XP004087618 ISSN: 0040-6090, page 98, paragraph 2; figure 5.
<i>SL</i>	Inoue et al.: "Low Thermal-Budget Fabrication of Sputtered-PZT Capacitor on Multilevel Interconnects for Embedded FeRAM, Silicon Systems REs. Labs. And ULSI Development Div., NEC 2000 IEEE
<i>SL</i>	Communication from European Patent Office dated June 6, 2004 and European Search Report dated June 4, 2004
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